



BOND PAD DEFECT CALCULATION USING GRIDLINES

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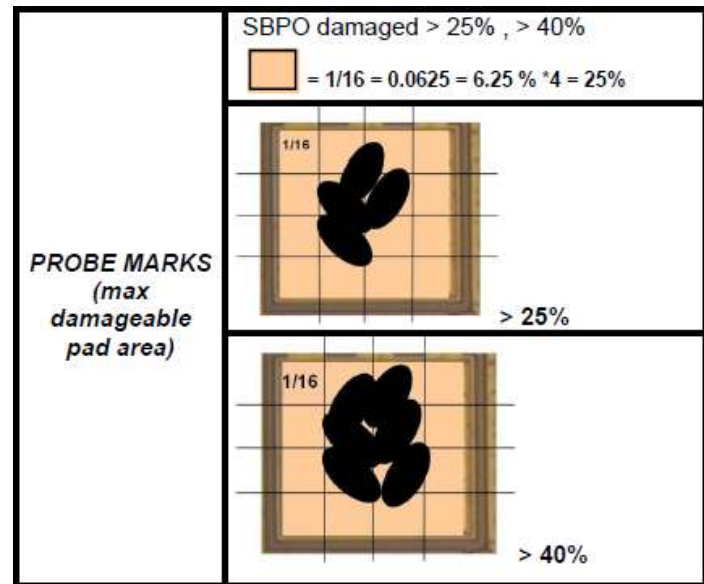
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PROJECT OBJECTIVE

- Provide specialized measurement tool for quantifying or measuring probe marks and bond pad-related defects, for Incoming Quality Control (IQC) station, Assembly Process Control, and for New Product Introduction (NPI)
- Zero cost implementation by utilizing existing software licenses and available resources
 - Instead of purchasing brand-new measurement equipment or software measurement tool, one big challenge is to come up with an innovative and cost-effective solution that will address quality-related difficulties by maximizing existing available resources

PROBLEM IDENTIFICATION – BOND PAD DEFECT USING VISUAL MEASUREMENT

- Previous methodology employed manual grids to measure or estimate the magnitude of the bond pad defect



Example of Bond Pad Defects That Need Measurement

SOLUTION IMPLEMENTATION

BEFORE				AFTER		
Sample	Manual Grid			Auto		
	Measurement	Dispo	Image	Measurement	Dispo	Image
1	1/16	MARGINAL		3.72%	ACCEPT	
2	>2/16	REJECT		10.25%	REJECT	
Loss: Low accuracy. Measurement is subjective, and through visual estimation.				Gain: Measurement is still subjective but with better accuracy. The measurement tool calculates real-time while pin-pointing the defects.		
Result: Sample 1 – no decision (marginal) Sample 2 – reject				Result: Sample 1 – accept, with 3.72% bond pad defect Sample 2 – reject, with 10.25% bond pad defect		